

April 1988 Revised August 1999

74F573

Octal D-Type Latch with 3-STATE Outputs

General Description

The 74F573 is a high speed octal latch with buffered common Latch Enable (LE) and buffered common Output Enable (\overline{OE}) inputs.

This device is functionally identical to the 74F373 but has different pinouts.

Features

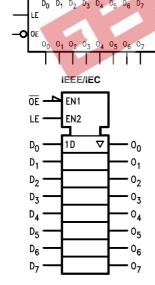
- Inputs and outputs on opposite sides of package allowing easy interface with microprocessors
- Useful as input or output port for microprocessors
- Functionally identical to 74F373
- 3-STATE outputs for bus interfacing
- Guaranteed 4000V minimum ESD protection

Ordering Code:

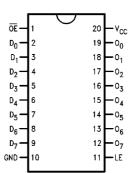
Order Number	Package Number	Package Description				
74F573SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide				
74F573SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide				
74F573PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide				

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}	
	Description	HIGH/LOW	Output I _{OH} /I _{OL}	
D ₀ –D ₇	Data Inputs	1.0/1.0	20 μA/-0.6 mA	
LE	Latch Enable Input (Active HIGH)	1.0/1.0	20 μA/-0.6 mA	
ŌĒ	3-STATE Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
O ₀ -O ₇	3-STATE Latch Outputs	150/40(33.3)	-3 mA/24 mA (20 mA)	

Functional Description

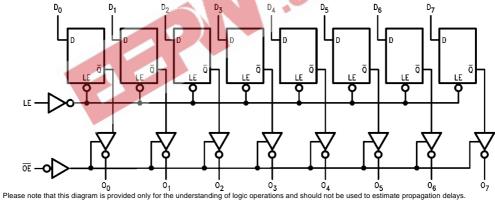
The 74F573 contains eight D-type latches with 3-state output buffers. When the Latch Enable (LE) input is HIGH, data on the $\boldsymbol{D}_{\boldsymbol{n}}$ inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D input changes. When LE is LOW the latches store the information that was present on the D inputs a setup time preceding the HIGH-to-LOW transition of LE. The 3-state buffers are controlled by the Output Enable (\overline{OE}) input. When \overline{OE} is LOW, the buffers are in the bi-state mode. When $\overline{\text{OE}}$ is HIGH the buffers are in the high impedance mode but this does not interfere with entering new data into the latches.

Function Table

	Inputs		Outputs
OE	LE	D	0
L	Н	Н	Н
L	Н	L	L
L	La	Χ	O ₀
Н	X	Χ	Z

- H = HIGH Voltage Level
 L = LOW Voltage Level

Logic Diagram



Absolute Maximum Ratings(Note 1)

-65°C to +150°C

Storage Temperature Ambient Temperature under Bias -55°C to +125°C Junction Temperature under Bias -55°C to +150°C

V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) $-30\ \text{mA}$ to $+5.0\ \text{mA}$

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

Standard Output –0.5V to $\ensuremath{\text{V}_{\text{CC}}}$ 3-STATE Output -0.5V to +5.5V

Current Applied to Output

twice the rated I_{OL} (mA) in LOW State (Max) ESD Last Passing Voltage (Min)

Conditions Free Air Ambient Temperature

Recommended Operating

0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

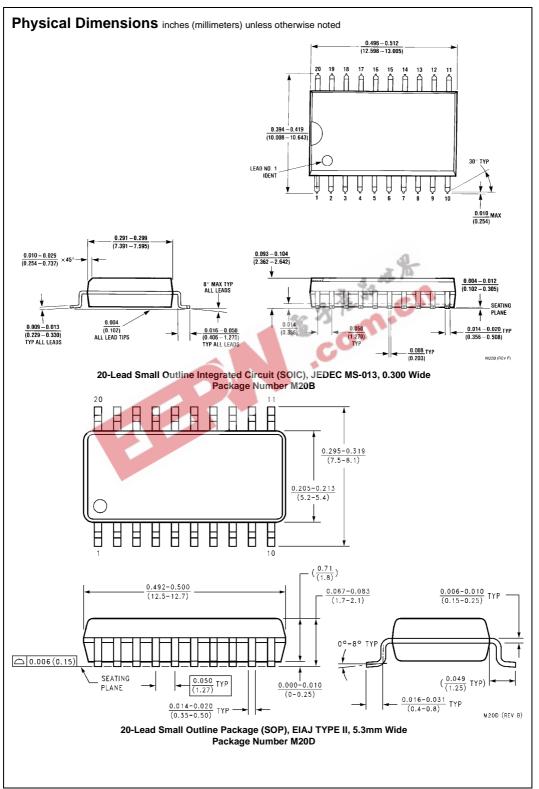
Symbol	Parameter		Min	Тур	Max	Units	V _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V_{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V_{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = −18 mA
V _{OH}	Output HIGH	10% V _{CC}	2.5	4	CIL		*	I _{OH} = -1 mA
	Voltage	10% V _{CC}	2.4		400	V	Min	$I_{OH} = -3 \text{ mA}$
		$5\% V_{CC}$	2.7			V	IVIIII	$I_{OH} = -1 \text{ mA}$
		5% V _{CC}	2.7					$I_{OH} = -3 \text{ mA}$
V _{OL}	Output LOW	10% V _{CC}			0.5	V	Min	I _{OL} = 24 mA
	Voltage	10% VCC			0.5	V	IVIIN	I _{OL} = 24 IIIA
I _{IH}	Input HIGH		7		20.0	μА	Max	V _{IN} = 2.7V
	Current				5.0	μΑ	IVIAX	V _{IN} = 2.7 V
I _{BVI}	Input HIGH Current				7.0	μА	Max	V _{IN} = 7.0V
	Breakdown Test			7.0	μΛ	IVIGA	V _{IN} = 7.0 V	
I _{CEX}	Output HIGH			50	μА	Max	V -V	
	Leakage Current						$V_{OUT} = V_{CC}$	
V_{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$
	Test		4.75			V	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				3.75	^	0.0	V _{IOD} = 150 mV
	Circuit Current				3.73	μΑ	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$
I _{OZH}	Output Leakage Current				50	μΑ	Max	V _{OUT} = 2.7V
l _{OZL}	Output Leakage Current				-50	μΑ	Max	V _{OUT} = 0.5V
los	Output Short-Circuit Current		-60		-150	mA	Max	$V_{OUT} = 0V$
I _{ZZ}	Bus Drainage Test				500	μΑ	0.0V	V _{OUT} = 5.25V
I _{CCL}	Power Supply Current			35	55	mA	Max	$V_O = LOW$
I _{CCZ}	Power Supply Current			35	55	mA	Max	$V_0 = HIGH Z$

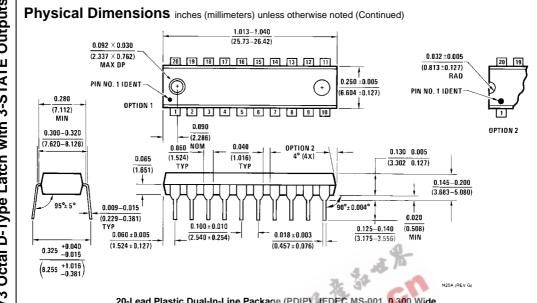
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50$ pF		Units
		Min	Тур	Max	Min	Max	Min	Max	
t _{PLH}	Propagation Delay	3.0	5.3	7.0	3.0	9.0	3.0	8.0	ns
t _{PHL}	D _n to O _n	2.0	3.7	6.0	2.0	7.0	2.0	6.5	115
t _{PLH}	Propagation Delay	5.0	9.0	11.0	5.0	13.5	5.0	12.0	no
t _{PHL}	LE to O _n	3.0	5.2	7.0	3.0	7.5	3.0	7.0	ns
t _{PZH}	Output Enable Time	2.0	5.0	8.0	2.0	10.0	2.0	9.0	
t _{PZL}		2.0	5.6	8.5	2.0	10.0	2.0	9.5	
t _{PHZ}	Output Disable Time	1.5	4.5	5.5	1.5	7.0	1.5	6.5	ns
t _{PLZ}		1.5	3.8	5.5	1.5	5.5	1.5	5.5	

AC Operating Requirements

		T _A =	= +25°C	$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$	$T_A = 0^{\circ}C$	to +70°C	
Symbol	Parameter	$\textbf{V}_{\textbf{CC}} = +5.0 \textbf{V}$		$V_{CC} = +5.0V$	V _{CC} = +5.0V		Units
		Min	Max	Min Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	2.0		2.0	2.0		
$t_S(L)$	D _n to LE	2.0		2.0	2.0		ns
t _H (H)	Hold Time, HIGH or LOW	3.0	20 X	3.0	3.0		115
$t_H(L)$	D _n to LE	3.5		4.0	3.5		
t _W (H)	LE Pulse Width, HIGH	4.0	4 444	4.0	4.0		ns





20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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